Se	arch No	otes	

Application/Control No.	Applicant(s)/Patent under Reexamination
10/500,696	KIM ET AL.
Examiner	Art Unit
Benjamin P. Blumel	1648

SEARCHED			
Class	Subclass	Date	Examiner
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
		DATE	EXMR
East		3/27/2007	BPB
Pubmed		3/27/2007	ВРВ
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